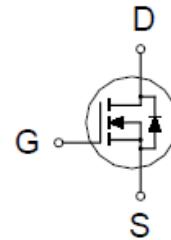
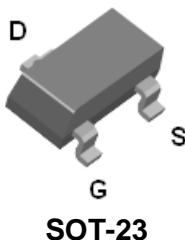


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PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
20V	50mΩ @ $V_{GS} = 4.5V$	4A



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 8	
Continuous Drain Current $T_A = 25^\circ C$	I_D	4	A
$T_A = 70^\circ C$	I_D	3.2	
Pulsed Drain Current ¹	I_{DM}	20	
Power Dissipation $T_A = 25^\circ C$	P_D	1.3	W
$T_A = 70^\circ C$	P_D	1	
Operating Junction & Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ³	$R_{\theta JA}$		100	°C / W

¹Pulse width limited by maximum junction temperature.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

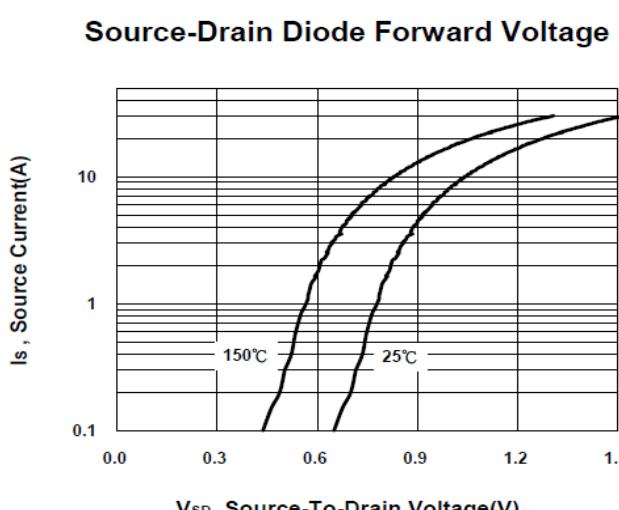
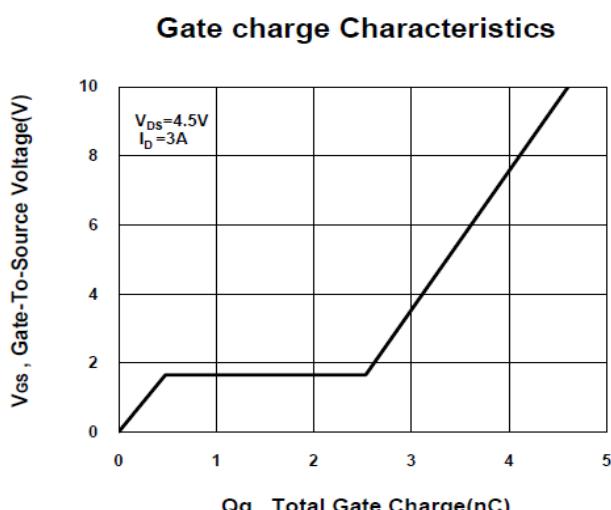
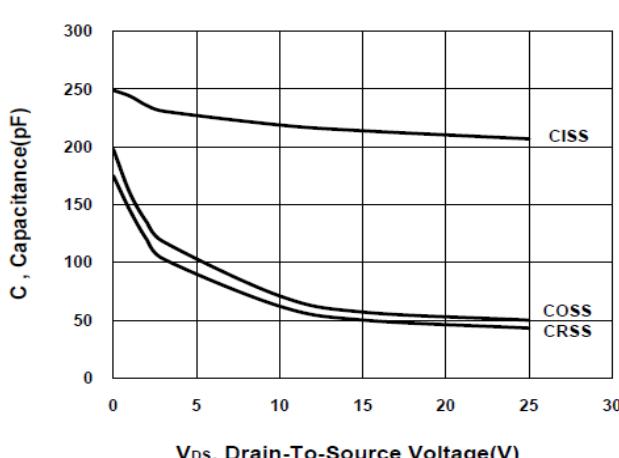
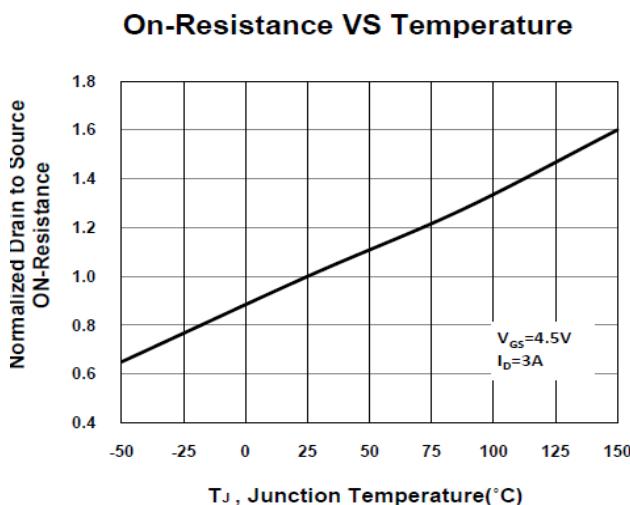
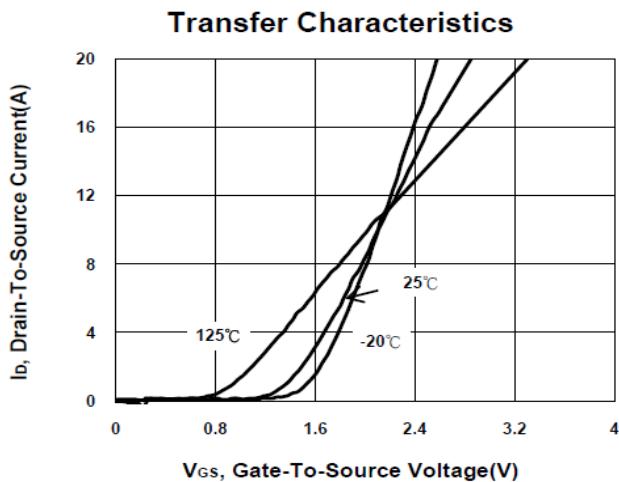
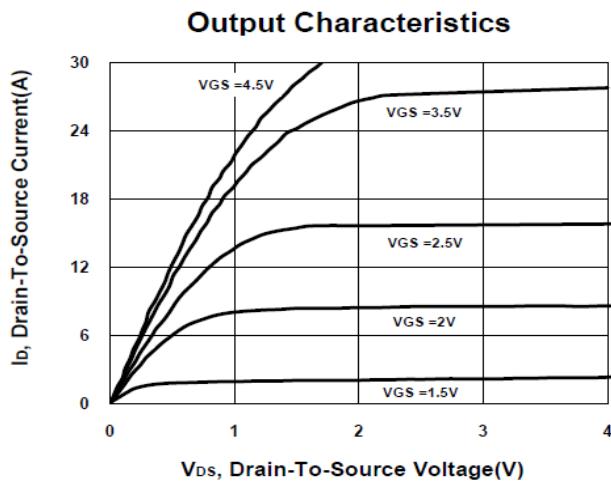
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	20			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	0.4	0.7	1.2	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 8\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 16\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 10\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 5\text{V}, V_{\text{GS}} = 4.5\text{V}$	20			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 2.5\text{V}, I_D = 1.5\text{A}$		50	85	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 3\text{A}$		37	50	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 5\text{V}, I_D = 3\text{A}$		15		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 10\text{V}, f = 1\text{MHz}$		236		pF
Output Capacitance	C_{oss}			75		
Reverse Transfer Capacitance	C_{rss}			69		
Total Gate Charge ²	Q_g	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, V_{\text{GS}} = 4.5\text{V}, I_D = 3\text{A}$		4.7		nC
Gate-Source Charge ²	Q_{gs}			0.5		
Gate-Drain Charge ²	Q_{gd}			2.4		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 10\text{V}$ $I_D \approx 3\text{A}, V_{\text{GS}} = 4.5\text{V}, R_{\text{GS}} = 6\Omega$		5		nS
Rise Time ²	t_r			72		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			25		
Fall Time ²	t_f			11		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				4	A
Forward Voltage ¹	V_{SD}	$I_F = 3\text{A}, V_{\text{GS}} = 0\text{V}$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 3\text{A}, dI_F/dt = 100 \text{ A}/\mu\text{s}$		9.6		nS
Reverse Recovery Charge	Q_{rr}			2		nC

¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

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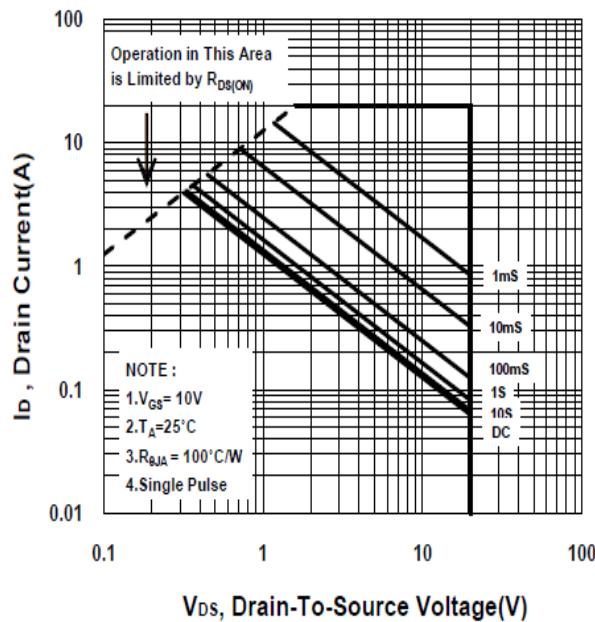
N-Channel Enhancement Mode MOSFET



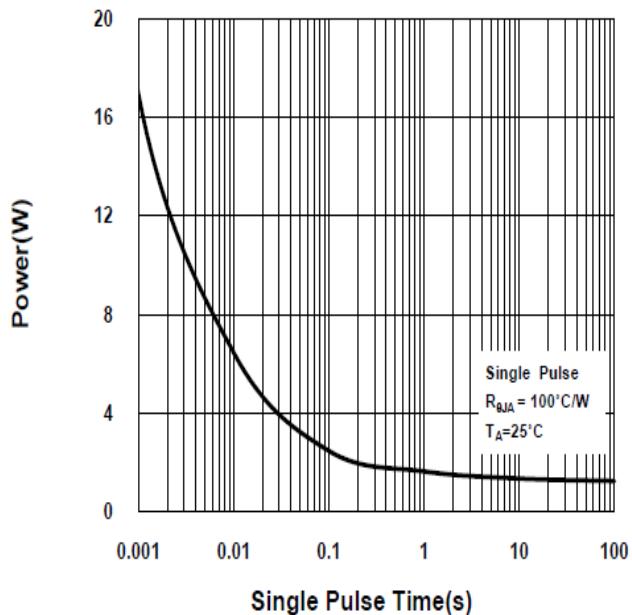
P5002CMG

N-Channel Enhancement Mode MOSFET

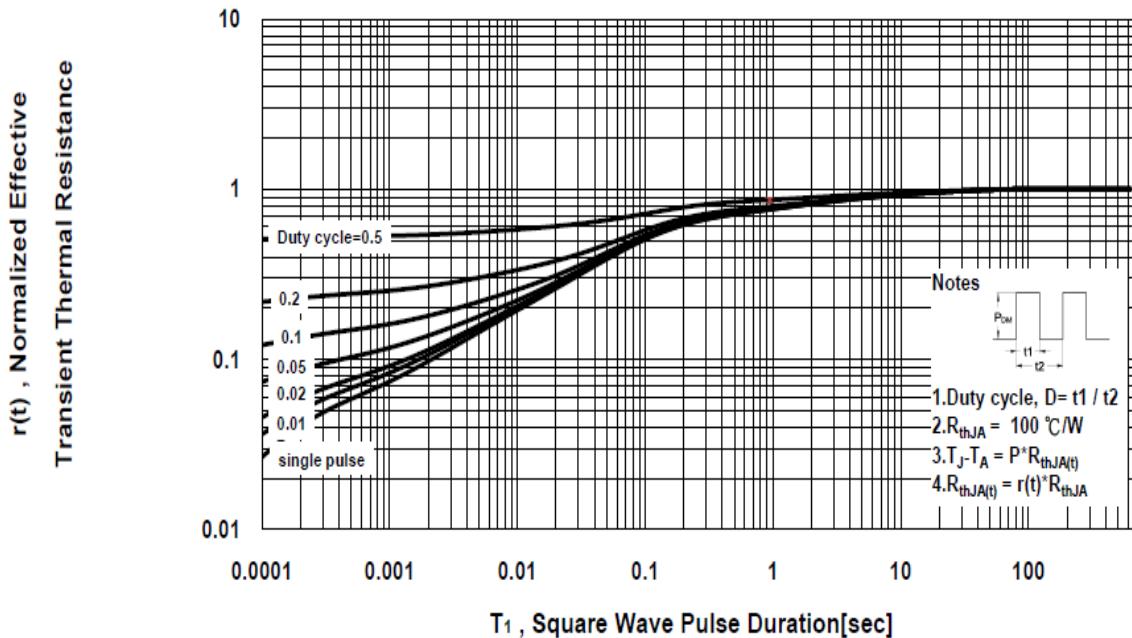
Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve



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Package Dimension

SOT-23-3 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A		1.05		H	0.1		0.2
B	2.4		3	I	0.3		0.6
C	1.4		1.73				
D	2.7		3.1				
E	1		1.31				
F	0		0.15				
G	0.3		0.5				

